



## **Provisionnal program**





## 3<sup>rd</sup> Workshop "Combined Analysis Using X-ray and Neutron Scattering " July 8-12, 2013, Caen (France)

Monday	Tuesday	Wednesday	Thursday	Friday
	9h  Classical Rietveld Analysis  Rietveld method in brief The Ph(y) parameter of the problematic texture in Rieveld Microstructural aspect of the profile How the deconvolution operates Le Bail extraction NL Least squares, genetic and simulated annealing	9h  Line Broadening Analysis  Line broadening due to size and microstrains  Williamson-Hall, Bertaut-Warren-Averbach, Popa  Size and microstrain distributions	9h  Residual Stress Analysis  Calculation of residual stress Characterization of macrostress Study of 2nd and 3rd order stresse Anisotropy of lattice strain response	9h <b>The combined solution</b> Algorithm Examples
		~10h30 / 11h : coffe break		
10h Welcome	Classical Crystallographic Texture Analysis  Quantitative Texture Analysis, measurements / Corrections  Direct Pole Figures, normalisation, inverse pole figures, ODF Resolution methods	X-ray reflectivity Analysis Specular reflectivity Fresnel, Parratt Formalisms Roughness Correlation functions	Phase Analysis Crystalline, amorphous Applications	Whole Pattern from images  Evaluation of the formation
		~12h30 / 14h : Lunch		
Introduction Fundamental aspect Technical description	Practical session Use of the MAUD software	Practical session Use of the MAUD software	Practical session Use of the MAUD software	
		~15h30 / 16h : coffe break		
Classical Rietveld Analysis Rietveld method in brief The Ph(y) parameter of the problematic texture in Rieveld Microstructural aspect of the profile How the deconvolution operates Le Bail extraction NL Least squares, genetic and simulated annealing	Practical session Use of the MAUD software	Practical session Use of the MAUD software	Practical session Use of the MAUD software	
	•	~18h End of the day		
	~19h Dinner		~19h Dinner	